

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: I. SHIMIZU et al
Serial No. 10/140,043
Filed: May 8, 2002

Group Art: 2133
Examiner: J. Kerveros
For: TEST SYSTEM AND MANUFACTURING OF
SEMICONDUCTOR DEVICE

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 15, 2004

Sir:

Prior to examination, please amend the above application
as follows.